

Diode EMCON 4 High Power Chip

FEATURES:

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1200V EMCON 4 technology •

small temperature coefficient

soft, fast switching • low reverse recovery charge

This chip is used for:

medium / high power modules •



Applications:

medium / high power drives •

Chip Type	V _R	I _F	Die Size	Package
IDC73D120T6H	1200V	150A	8.15 x 9.00 mm ²	sawn on foil

MECHANICAL PARAMETER:

Raster size	8.15 x 9.00				
Area total / active	73.35 / 59.89	mm ²			
Anode pad size	7.196 x 8.046]			
Thickness	120	μm			
Wafer size	150	mm			
Flat position	180	deg			
Max. possible chips per wafer	187 pcs				
Passivation frontside	Photoimide				
Pad metall	3200 nm AlSiCu				
Backside metall	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	Al, ≤500µm				
Reject ink dot size Ø 0.65mm; max 1.2mm					
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



Maximum Ratings

Parameter	Symbol	Condition	Value	Unit		
Repetitive peak reverse voltage	V _{RRM}		1200	V		
Continuous forward current limited by	1_		1)			
T _{jmax}	1 _F			А		
Maximum repetitive forward current	1		300			
limited by T _{jmax}	I _{FRM}		300			
Maximum junction and storage temperature	T _{vj,max} , T _{stg}		-40+175	°C		
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{F,max} = 300A, V_{R,max} = 1200V, T_{vj,op} \le 150^{\circ}C, P_{max} = tbd kW$					

¹⁾ depending on thermal properties of assembly

²⁾ not subject to production test - verified by design/characterisation

Static Electrical Characteristics (tested on wafer), $T_i=25$ °C

Parameter	Symbol	Condi	Value			Unit		
Falameter	Symbol	Cond	litons	min. Typ. max.		max.		
Reverse leakage current	/ _R	V _R =1200V	<i>T_j</i> =25 ° <i>C</i>			26	μΑ	
Cathode-Anode breakdown Voltage	V _{Br}	I _R =0.25mA	<i>T_j</i> =25°C	1200			V	
Forward voltage drop	V _F	I _F =150A	<i>T_j</i> =25 ° <i>C</i>	1.55	1.9	2.25	V	

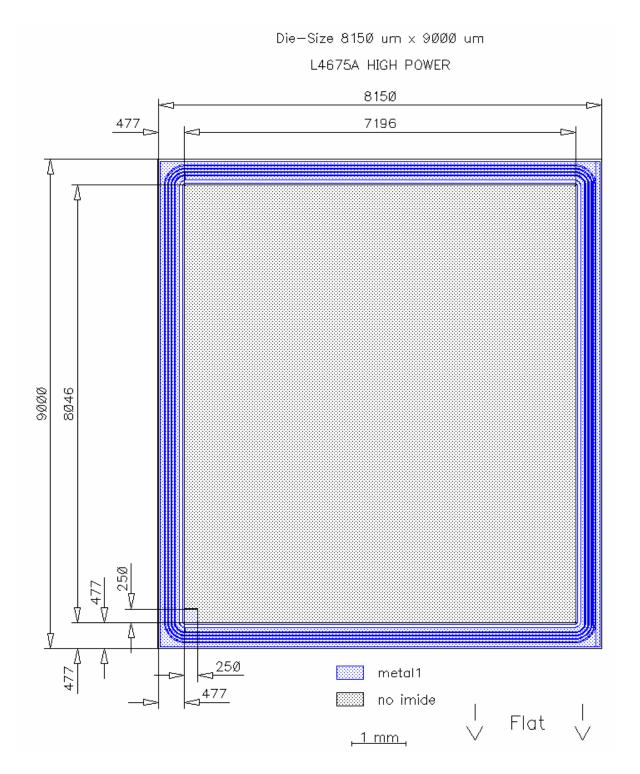
Dynamic Electrical Characteristics inductive load (not subject to production test - verified by design/characterization)

Parameter	Symbol	Conditions		Value ²⁾			Unit
Falallelel	Symbol			min.	Тур.	max.	
Peak reverse recovery current	/ _{RM}	$I_{F}=A$ di/dt=A/ms $V_{R}=V$ $V_{GE}=-15V$	$T_j = 25 \ ^{\circ}C$ $T_j = 125 \ ^{\circ}C$ $T_j = 150 \ ^{\circ}C$		tbd		A
Reverse recovery charge	Q _r	$I_{F}=A$ di/dt=A/ms $V_{R}=V$ $V_{GE}=-15V$	$T_j = 25 \ ^{\circ}C$ $T_j = 125 \ ^{\circ}C$ $T_j = 150 \ ^{\circ}C$		tbd		μC
Reverse recovery energy	E _{rec}	$I_{F}=A$ di/dt=A/ms $V_{R}=V$ $V_{GE}=-15V$	$T_{j} = 25 \ ^{\circ}C$ $T_{j} = 125 \ ^{\circ}C$ $T_{j} = 150 \ ^{\circ}C$		tbd		mJ

²⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

tbd

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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